

Philips Semiconductors

N AMER PHILIPS/DISCRETE

BSS123

N-channel enhancement mode vertical D-MOS transistor

Data sheet	
status	Product specification
date of issue	July 1993

FEATURES

- Direct interface to C-MOS, TTL, etc.
- High-speed switching
- No secondary breakdown.

DESCRIPTION

N-channel enhancement mode vertical D-MOS transistor in a SOT23 envelope, intended for use as a line current interruptor in telephone sets and for applications in relay, high-speed and line transformer drivers.

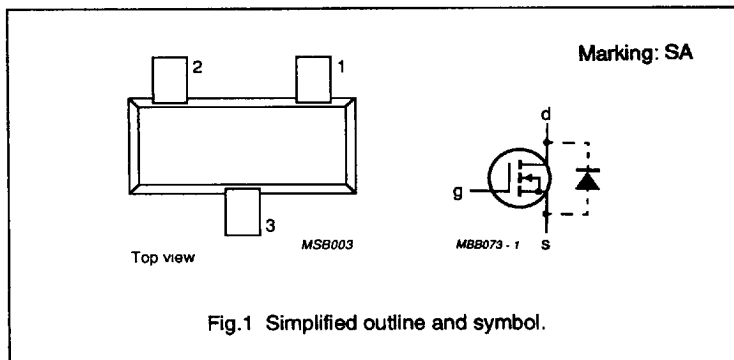
PINNING - SOT23

PIN	DESCRIPTION
1	gate
2	source
3	drain

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MAX.	UNIT
V_{DS}	drain-source voltage		100	V
I_D	drain current	DC value	150	mA
$R_{DS(on)}$	drain-source on-resistance	$I_D = 120 \text{ mA}$ $V_{GS} = 10 \text{ V}$	6	Ω
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$ $V_{GS} = V_{DS}$	2.8	V

PIN CONFIGURATION



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BSS123**LIMITING VALUES**

In accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	drain-source voltage		—	100	V
$\pm V_{GSO}$	gate-source voltage	open drain	—	20	V
I_D	drain current	DC value	—	150	mA
I_{DM}	drain current	peak value	—	600	mA
P_{tot}	total power dissipation	up to $T_{amb} = 25\text{ °C}$	—	250	mW
T_{stg}	storage temperature range		—65	150	°C
T_J	junction temperature		—	150	°C

THERMAL RESISTANCE

SYMBOL	PARAMETER	VALUE	UNIT
$R_{th\ j-a}$	from junction to ambient (note 1)	500	K/W

Note

1. Device mounted on a FR4 printboard.

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CHARACTERISTICS
 $T_j = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10\text{ }\mu\text{A}$ $V_{GS} = 0$	100	—	—	V
I_{DSS}	drain-source leakage current	$V_{DS} = 60\text{ V}$ $V_{GS} = 0$	—	—	10	nA
$\pm I_{GSS}$	gate-source leakage current	$\pm V_{GS} = 20\text{ V}$ $V_{DS} = 0$	—	—	10	nA
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1\text{ mA}$ $V_{GS} = V_{DS}$	0.8	—	2.8	V
$R_{DS(on)}$	drain-source on-resistance	$I_D = 120\text{ mA}$ $V_{GS} = 10\text{ V}$	—	3	6	Ω
$ Y_{fs} $	transfer admittance	$I_D = 120\text{ mA}$ $V_{DS} = 25\text{ V}$	80	140	—	mS
C_{iss}	input capacitance	$V_{DS} = 25\text{ V}$ $V_{GS} = 0$ $f = 1\text{ MHz}$	—	24	—	pF
C_{oss}	output capacitance	$V_{DS} = 25\text{ V}$ $V_{GS} = 0$ $f = 1\text{ MHz}$	—	15	—	pF
C_{rss}	feedback capacitance	$V_{DS} = 25\text{ V}$ $V_{GS} = 0$ $f = 1\text{ MHz}$	—	4	—	pF
Switching times (see Figs 2 and 3)						
t_{on}	turn-on time	$I_D = 200\text{ mA}$ $V_{DD} = 50\text{ V}$ $V_{GS} = 0\text{ to }10\text{ V}$	—	4	10	ns
t_{off}	turn-off time	$I_D = 250\text{ mA}$ $V_{DD} = 50\text{ V}$ $V_{GS} = 0\text{ to }10\text{ V}$	—	10	20	ns

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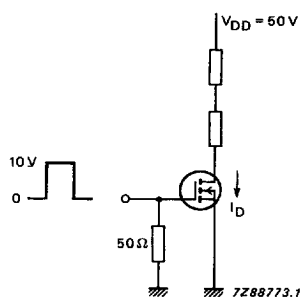


Fig.2 Switching time test circuit.

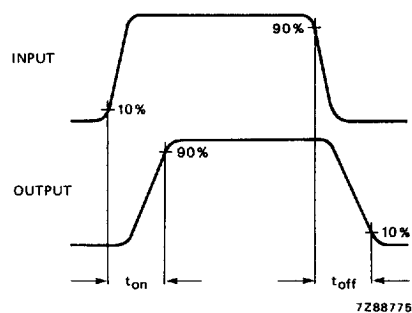


Fig.3 Input and output waveforms.